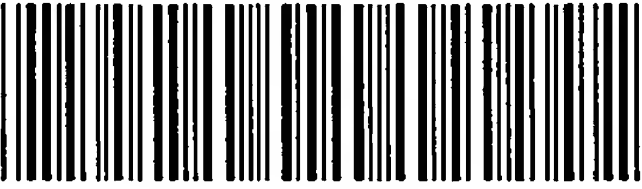


<div>Search Notes</div> <div></div>	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/646,651	ZWADLO ET AL.	
	Examiner	Art Unit	
	Hai C. Pham	2861	

SEARCHED			
Class	Subclass	Date	Examiner
347	234, 241, 244, 248, 256, 258	4/16/2005	HP
430	30, 201	4/16/2005	HP

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
east	4/16/2005	HP